Unit: mm

TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (π–MOSV)

2SK2862

DC-DC Converter, Relay Drive and Motor Drive Applications

 $\begin{array}{ll} \bullet & Low\ drain-source\ ON\ resistance & : RDS\ (ON) = 2.9\ \Omega\ (typ.) \\ \bullet & High\ forward\ transfer\ admittance & : |Y_{fs}| = 1.7\ S\ (typ.) \\ \bullet & Low\ leakage\ current & : IDSS = 100\ \mu A\ (max)\ (V_{DS} = 500\ V) \\ \bullet & Enhancement\ mode & : V_{th} = 2.0 \sim 4.0\ V\ (V_{DS} = 10\ V,\ I_{D} = 1\ mA) \end{array}$

Absolute Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit
Drain-source voltage		V_{DSS}	500	V
Drain-gate voltage	e (R _{GS} = 20 kΩ)	V_{DGR}	500	V
Gate-source volta	ge	V _{GSS}	±30	V
Drain current	DC (Note 1)	ID	3	Α
	Pulse (t = 1 ms) (Note 1)	I _{DP}	5	А
	Pulse (t = 100 µs) (Note 1)	I _{DP}	12	А
Drain power dissip	ation (Tc = 25°C)	P _D	25	W
Single pulse avalanche energy (Note 2)		E _{AS}	112	mJ
Avalanche current		I _{AR}	2	Α
Repetitive avalanc	he energy (Note 3)	E _{AR}	2.5	mJ
Channel temperatu	ıre	T _{ch}	150	°C
Storage temperature range		T _{stg}	-55~150	°C

Weight: 1.9 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Thermal Characteristics

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R _{th (ch-c)}	5.0	°C/W
Thermal resistance, channel to ambient	R _{th (ch-a)}	62.5	°C/W

Note 1: Ensure that the channel temperature does not exceed 150°C.

Note 2: V_{DD} = 90 V, starting T_{ch} = 25°C, L = 48.4 mH, R_{G} = 25 Ω , I_{AR} = 2 A

Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device.

Please handle with caution.



Electrical Characteristics (Ta = 25°C)

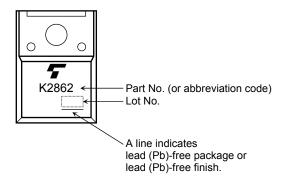
Charac	cteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cu	ırrent	I _{GSS}	V _{GS} = ±25 V, V _{DS} = 0 V	_	_	±10	μΑ
Gate-source bre	eakdown voltage	V (BR) GSS	$I_G = \pm 10 \mu A, V_{DS} = 0 V$	±30	_	_	V
Drain cut-off cu	rrent	I _{DSS}	V _{DS} = 500 V, V _{GS} = 0 V	_	_	100	μA
Drain-source br	eakdown voltage	V (BR) DSS	I _D = 10 mA, V _{GS} = 0 V	500	_	_	V
Gate threshold v	/oltage	V_{th}	V _{DS} = 10 V, I _D = 1 mA	2.0	_	4.0	V
Drain-source O	N resistance	R _{DS} (ON)	V _{GS} = 10 V, I _D = 1 A	_	2.9	3.2	Ω
Forward transfer	r admittance	Y _{fs}	V _{DS} = 10 V, I _D = 1 A	0.8	1.7	_	S
Input capacitano	ce	C _{iss}		_	380	_	
Reverse transfer capacitance		C _{rss}	V _{DS} = 10 V, V _{GS} = 0 V, f = 1 MHz		40	_	pF
Output capacitance		Coss			120	_	
Switching time	Rise time	t _r	$V_{GS} \xrightarrow{0V} \prod_{ID=1A} V_{OUT}$ $R_{L} = 200\Omega$ $V_{DD} = 200V$	_	15	_	
	Turn-on time	t _{on}		_	25	_	ne
	Fall time	t _f		ı	20	_	ns
	Turn-off time	t _{off}	Duty $\leq 1\%$, $t_{\rm W} = 10 \mu {\rm s}$		80	_	
Total gate charge (gate–source plus gate–drain)		Q_{g}		_	9	_	
Gate-source charge		Q _{gs}	$V_{DD} \approx 400 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 2 \text{ A}$		5	_	nC
Gate-drain ("miller") Charge		Q_{gd}		_	4	_	

Source-Drain Ratings and Characteristics (Ta = 25°C)

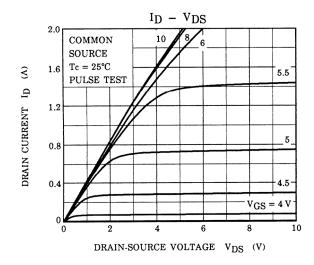
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I _{DR}	_	_	_	3	Α
Pulse drain reverse current (Note 1)	I _{DRP}	t = 1 ms	_	_	5	Α
	I _{DRP}	t = 100 μs	_	_	12	Α
Forward voltage (diode)	V_{DSF}	I _{DR} = 2 A, V _{GS} = 0 V	_	_	-1.5	V
Reverse recovery time	t _{rr}	I _{DR} = 2 A, V _{GS} = 0 V	_	1000	_	ns
Reverse recovery charge	Qrr	dl _{DR} / dt = 100 A / μs	_	3.5	_	μC

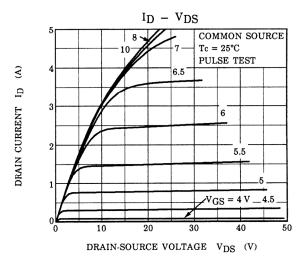
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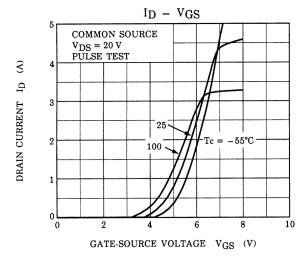
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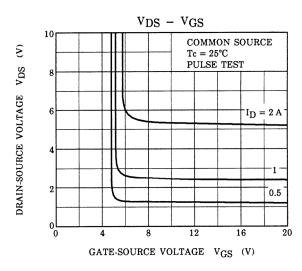


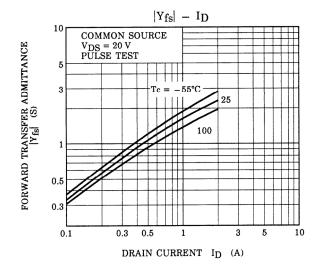
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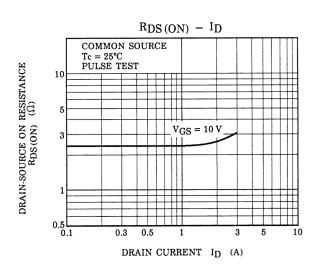




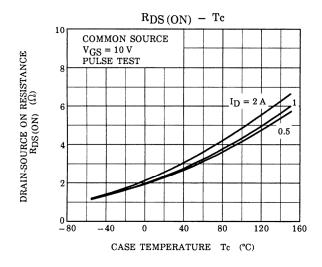


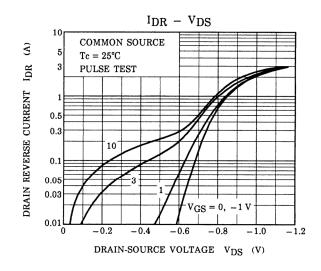


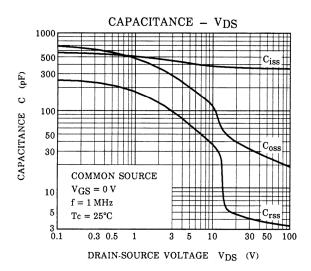


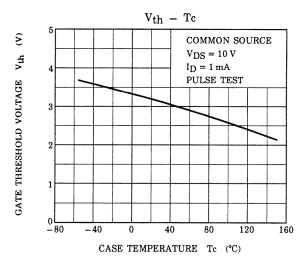


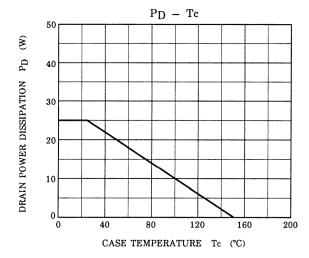
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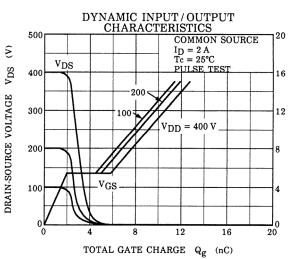






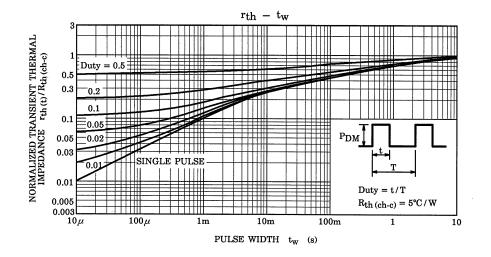


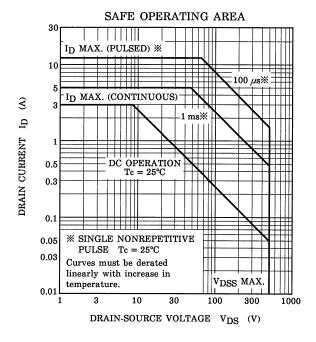


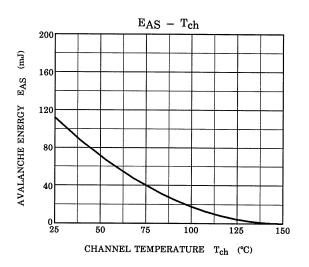


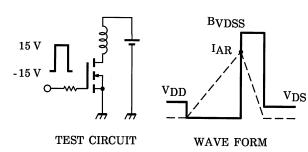
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 VGS









$$\begin{aligned} &RG = 25 \ \Omega \\ &V_{DD} = 90 \ V, \ L = 48.4 \ mH \end{aligned} \qquad EAS = \frac{1}{2} \cdot L \cdot I^2 \cdot \left(\frac{B_{VDSS}}{B_{VDSS} - V_{DD}} \right)$$

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